

Notice of References Cited		Application/Control No. 10/559,944	Applicant(s)/Patent Under Reexamination BAEK ET AL.	
		Examiner SATISH CHANDRA	Art Unit 1716	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,186,756	02-1993	Benko et al.	118/730
*	B	US-2004/0082171	04-2004	Shin et al.	438/689
*	C	US-2006/0000412	01-2006	Ahn et al.	118/715
*	D	US-2005/0224181	10-2005	Merry et al.	156/345.35
*	E	US-2003/0041971	03-2003	Kido et al.	156/345.33
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.